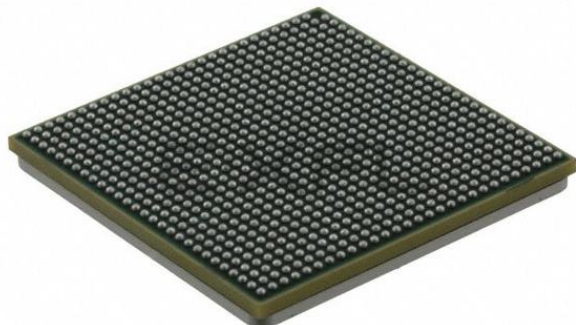




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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	800MHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8544evtang

- Three PCI Express interfaces
 - Two $\times 4$ link width interfaces and one $\times 1$ link width interface
 - PCI Express 1.0a compatible
 - Auto-detection of number of connected lanes
 - Selectable operation as root complex or endpoint
 - Both 32- and 64-bit addressing
 - 256-byte maximum payload size
 - Virtual channel 0 only
 - Traffic class 0 only
 - Full 64-bit decode with 32-bit wide windows
- Power management
 - Supports power saving modes: doze, nap, and sleep
 - Employs dynamic power management, which automatically minimizes power consumption of blocks when they are idle
- System performance monitor
 - Supports eight 32-bit counters that count the occurrence of selected events
 - Ability to count up to 512 counter-specific events
 - Supports 64 reference events that can be counted on any of the 8 counters
 - Supports duration and quantity threshold counting
 - Burstiness feature that permits counting of burst events with a programmable time between bursts
 - Triggering and chaining capability
 - Ability to generate an interrupt on overflow
- System access port
 - Uses JTAG interface and a TAP controller to access entire system memory map
 - Supports 32-bit accesses to configuration registers
 - Supports cache-line burst accesses to main memory
 - Supports large block (4-Kbyte) uploads and downloads
 - Supports continuous bit streaming of entire block for fast upload and download
- IEEE Std 1149.1TM-compliant, JTAG boundary scan
- 783 FC-PBGA package

4.2 Real-Time Clock Timing

The RTC input is sampled by the platform clock (CCB clock). The output of the sampling latch is then used as an input to the counters of the PIC and the TimeBase unit of the e500. There is no jitter specification. The minimum pulse width of the RTC signal should be greater than $2 \times$ the period of the CCB clock. That is, minimum clock high time is $2 \times t_{CCB}$, and minimum clock low time is $2 \times t_{CCB}$. There is no minimum RTC frequency; RTC may be grounded if not needed.

4.3 eTSEC Gigabit Reference Clock Timing

Table 7 provides the eTSEC gigabit reference clocks (EC_GTX_CLK125) AC timing specifications for the MPC8544E.

Table 7. EC_GTX_CLK125 AC Timing Specifications

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Notes
EC_GTX_CLK125 frequency	f_{G125}	—	125	—	MHz	—
EC_GTX_CLK125 cycle time	t_{G125}	—	8	—	ns	—
EC_GTX_CLK rise and fall time LV _{DD} , TV _{DD} = 2.5 V LV _{DD} , TV _{DD} = 3.3 V	t_{G125R}/t_{G125F}	—	—	0.75 1.0	ns	1
EC_GTX_CLK125 duty cycle GMII, TBI 1000Base-T for RGMII, RTBI	t_{G125H}/t_{G125L}	45 47	—	55 53	%	2

Notes:

1. Rise and fall times for EC_GTX_CLK125 are measured from 0.5 and 2.0 V for L/TV_{DD} = 2.5 V, and from 0.6 and 2.7 V for L/TV_{DD} = 3.3 V.
2. EC_GTX_CLK125 is used to generate the GTX clock for the eTSEC transmitter with 2% degradation. EC_GTX_CLK125 duty cycle can be loosened from 47%/53% as long as the PHY device can tolerate the duty cycle generated by the eTSEC GTX_CLK. See Section 8.7.4, "RGMII and RTBI AC Timing Specifications," for duty cycle for 10Base-T and 100Base-T reference clock.

4.4 Platform to FIFO Restrictions

Please note the following FIFO maximum speed restrictions based on platform speed.

For FIFO GMII mode:

$$\text{FIFO TX/RX clock frequency} \leq \text{platform clock frequency} \div 4.2$$

For example, if the platform frequency is 533 MHz, the FIFO Tx/Rx clock frequency should be no more than 127 MHz.

For FIFO encoded mode:

$$\text{FIFO TX/RX clock frequency} \leq \text{platform clock frequency} \div 3.2$$

For example, if the platform frequency is 533 MHz, the FIFO Tx/Rx clock frequency should be no more than 167 MHz.

9 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals MDIO (management data input/output) and MDC (management data clock). The electrical characteristics for GMII, RGMII, RMII, TBI, and RTBI are specified in “[Section 8, “Enhanced Three-Speed Ethernet \(eTSEC\), MII Management.”](#)”

9.1 MII Management DC Electrical Characteristics

The MDC and MDIO are defined to operate at a supply voltage of 3.3 V. The DC electrical characteristics for MDIO and MDC are provided in [Table 40](#).

Table 40. MII Management DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Supply voltage (3.3 V)	OV_{DD}	3.135	3.465	V	—
Output high voltage ($OV_{DD} = \text{Min}$, $I_{OH} = -1.0 \text{ mA}$)	V_{OH}	2.10	3.60	V	—
Output low voltage ($OV_{DD} = \text{Min}$, $I_{OL} = 1.0 \text{ mA}$)	V_{OL}	GND	0.50	V	—
Input high voltage	V_{IH}	1.95	—	V	—
Input low voltage	V_{IL}	—	0.90	V	—
Input high current ($OV_{DD} = \text{Max}$, $V_{IN} = 2.1 \text{ V}$)	I_{IH}	—	40	μA	1
Input low current ($OV_{DD} = \text{Max}$, $V_{IN} = 0.5 \text{ V}$)	I_{IL}	-600	—	μA	—

Note:

1. The symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

9.2 MII Management AC Electrical Specifications

[Table 41](#) provides the MII management AC timing specifications.

Table 41. MII Management AC Timing Specifications

At recommended operating conditions with OV_{DD} is 3.3 V $\pm$ 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
MDC frequency	f_{MDC}	—	2.5	—	MHz	2
MDC period	t_{MDC}	—	400	—	ns	—
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	—
MDC to MDIO delay	t_{MDKHDX}	$(16 \times t_{plb_clk}) - 3$	—	$(16 \times t_{plb_clk}) + 3$	ns	3, 4
MDIO to MDC setup time	t_{MDDVKH}	5	—	—	ns	—
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	—
MDC rise time	t_{MDCR}	—	—	10	ns	—

Table 48. Local Bus General Timing Parameters—PLL Bypassed (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus clock to data valid for LAD/LDP	$t_{LBKLOV2}$	—	1.6	ns	4
Local bus clock to address valid for LAD, and LALE	$t_{LBKLOV3}$	—	1.6	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKLOX1}$	–4.1	—	ns	4
Output hold from local bus clock for LAD/LDP	$t_{LBKLOX2}$	–4.1	—	ns	4
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKLOZ1}$	—	1.4	ns	7
Local bus clock to output high impedance for LAD/LDP	$t_{LBKLOZ2}$	—	1.4	ns	7

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to local bus clock for PLL bypass mode. Timings may be negative with respect to the local bus clock because the actual launch and capture of signals is done with the internal launch/capture clock, which proceeds LCLK by t_{LBKHK1} .
3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
4. All signals are measured from $BV_{DD}/2$ of the rising edge of local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
5. Input timings are measured at the pin.
6. The value of t_{LBOTOT} is the measurement of the minimum time between the negation of LALE and any change in LAD.
7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

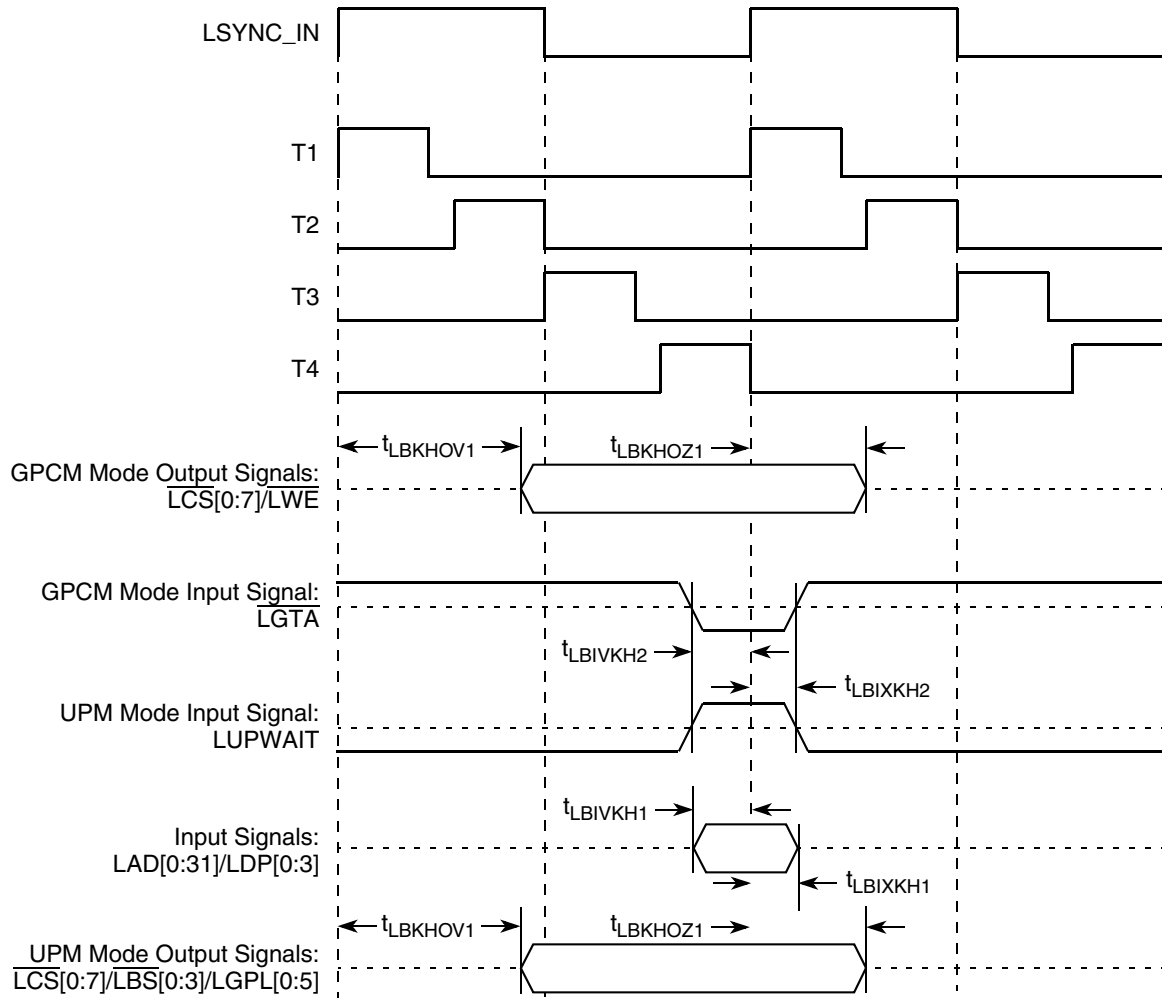


Figure 32. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 8 or 16 (PLL Enabled)

Table 50. JTAG AC Timing Specifications (Independent of SYSCLK)¹ (continued)

At recommended operating conditions (see Table 3).

Parameter	Symbol ²	Min	Max	Unit	Notes
JTAG external clock to output high impedance:				ns	5
Boundary-scan data	t_{JTKLDZ}	3	19		
TDO	t_{JTKLOZ}	3	9		

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of t_{CLK} to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50- Ω load (see Figure 34). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. The symbols used for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{JTDVXH} symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{JTG} clock reference (K) going to the high (H) state or setup time. Also, t_{JTDVXH} symbolizes JTAG timing (JT) with respect to the time data input signals (D) went invalid (X) relative to the t_{JTG} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
3. $\overline{TRST}$ is an asynchronous level sensitive signal. The setup time is for test purposes only.
4. Non-JTAG signal input timing with respect to t_{CLK} .
5. Non-JTAG signal output timing with respect to t_{CLK} .

Figure 34 provides the AC test load for TDO and the boundary-scan outputs.

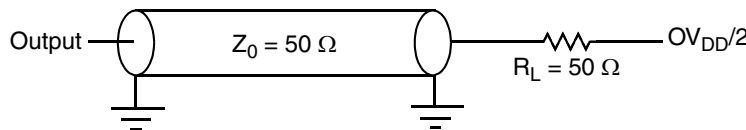

Figure 34. AC Test Load for the JTAG Interface

Figure 35 provides the JTAG clock input timing diagram.

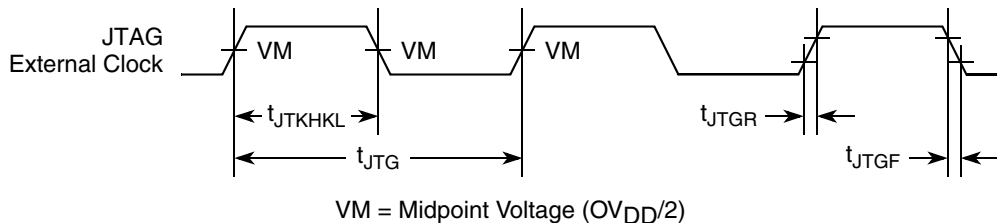
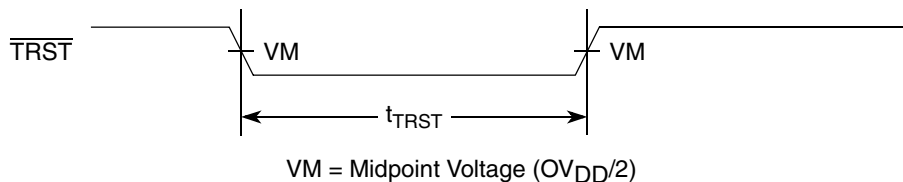

Figure 35. JTAG Clock Input Timing Diagram

Figure 36 provides the $\overline{TRST}$ timing diagram.


Figure 36. $\overline{TRST}$ Timing Diagram

- For **external DC-coupled** connection, as described in [Section 16.2.1, “SerDes Reference Clock Receiver Characteristics,”](#) the maximum average current requirements sets the requirement for average voltage (common mode voltage) to be between 100 and 400 mV. [Figure 46](#) shows the SerDes reference clock input requirement for DC-coupled connection scheme.
- For **external AC-coupled** connection, there is no common mode voltage requirement for the clock driver. Since the external AC-coupling capacitor blocks the DC level, the clock driver and the SerDes reference clock receiver operate in different command mode voltages. The SerDes reference clock receiver in this connection scheme has its common mode voltage set to SGND_SRDSn. Each signal wire of the differential inputs is allowed to swing below and above the command mode voltage (SGND_SRDSn). [Figure 47](#) shows the SerDes reference clock input requirement for AC-coupled connection scheme.
- **Single-ended Mode**
 - The reference clock can also be single-ended. The SDn_REF_CLK input amplitude (single-ended swing) must be between 400 and 800 mV peak-peak (from Vmin to Vmax) with SDn_REF_CLK either left unconnected or tied to ground.
 - The SDn_REF_CLK input average voltage must be between 200 and 400 mV. [Figure 48](#) shows the SerDes reference clock input requirement for single-ended signaling mode.
 - To meet the input amplitude requirement, the reference clock inputs might need to be DC or AC-coupled externally. For the best noise performance, the reference of the clock could be DC or AC-coupled into the unused phase (SDn_REF_CLK) through the same source impedance as the clock input (SDn_REF_CLK) in use.

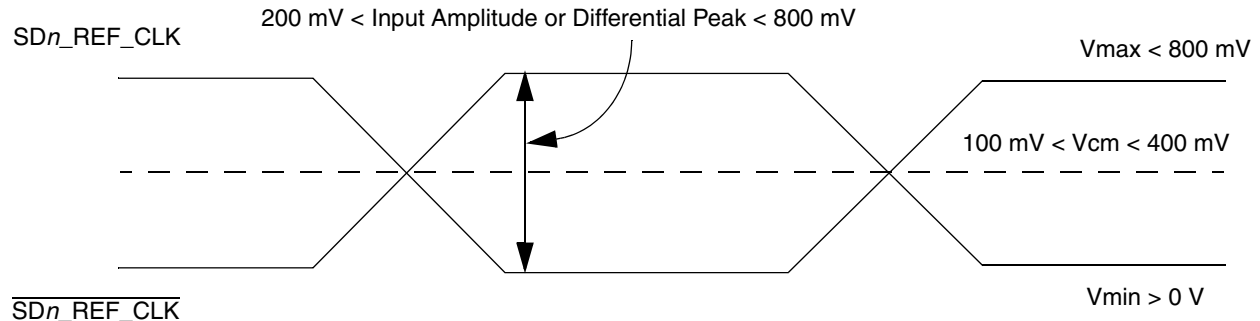


Figure 46. Differential Reference Clock Input DC Requirements (External DC-Coupled)

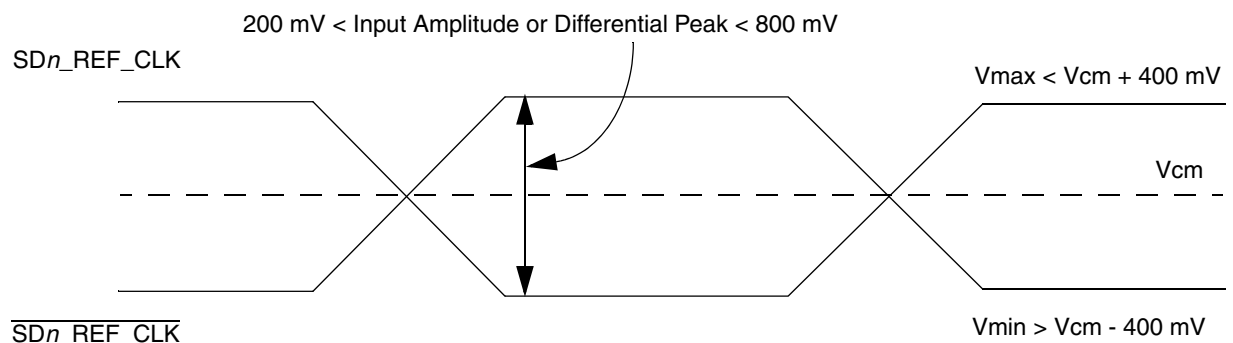


Figure 47. Differential Reference Clock Input DC Requirements (External AC-Coupled)

Table 59. Differential Transmitter (TX) Output Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Unit	Comments
$V_{TX-RCV-DETECT}$	Amount of voltage change allowed during receiver detection	—	—	600	mV	The total amount of voltage change that a transmitter can apply to sense whether a low impedance receiver is present. See Note 6.
$V_{TX-DC-CM}$	TX DC common mode voltage	0	—	3.6	V	The allowed DC common mode voltage under any conditions. See Note 6.
$I_{TX-SHORT}$	TX short circuit current limit	—	—	90	mA	The total current the transmitter can provide when shorted to its ground.
$T_{TX-IDLE-MIN}$	Minimum time spent in electrical idle	50	—	—	UI	Minimum time a transmitter must be in electrical idle utilized by the receiver to start looking for an electrical idle exit after successfully receiving an electrical idle ordered set.
$T_{TX-IDLE-SET-TO-IDLE}$	Maximum time to transition to a valid electrical idle after sending an electrical idle ordered set	—	—	20	UI	After sending an electrical idle ordered set, the transmitter must meet all electrical idle specifications within this time. This is considered a debounce time for the transmitter to meet electrical idle after transitioning from LO.
$T_{TX-IDLE-TO-DIFF-DATA}$	Maximum time to transition to valid TX specifications after leaving an electrical idle condition	—	—	20	UI	Maximum time to meet all TX specifications when transitioning from electrical idle to sending differential data. This is considered a debounce time for the TX to meet all TX specifications after leaving electrical idle.
$RL_{TX-DIFF}$	Differential return loss	12	—	—	dB	Measured over 50 MHz to 1.25 GHz. See Note 4.
RL_{TX-CM}	Common mode return loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz. See Note 4.
$Z_{TX-DIFF-DC}$	DC differential TX impedance	80	100	120	Ω	TX DC differential mode low impedance.
Z_{TX-DC}	Transmitter DC impedance	40	—	—	Ω	Required TX D+ as well as D– DC Impedance during all states.
$L_{TX-SKEW}$	Lane-to-lane output skew	—	—	500 + 2 UI	ps	Static skew between any two transmitter lanes within a single link.
C_{TX}	AC coupling capacitor	75	—	200	nF	All transmitters shall be AC coupled. The AC coupling is required either within the media or within the transmitting component itself.

Table 60. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Units	Comments
$T_{RX-EYE-MEDIAN-to-MAX-JITTER}$	Maximum time between the jitter median and maximum deviation from the median	—	—	0.3	UI	Jitter is defined as the measurement variation of the crossing points ($V_{RX-DIFFp-p} = 0$ V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI. See Notes 2, 3, and 7.
$V_{RX-CM-ACp}$	AC peak common mode input voltage	—	—	150	mV	$V_{RX-CM-ACp} = V_{RXD+} - V_{RXD-} \div 2 - V_{RX-CM-DC}$ $V_{RX-CM-DC} = DC_{(avg)} \text{ of } V_{RX-D+} - V_{RX-D-} /2$ See Note 2.
$RL_{RX-DIFF}$	Differential return loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at +300 and –300 mV, respectively. See Note 4.
RL_{RX-CM}	Common mode return loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at 0 V. See Note 4.
$Z_{RX-DIFF-DC}$	DC differential input impedance	80	100	120	Ω	RX DC differential mode impedance. See Note 5.
Z_{RX-DC}	DC input impedance	40	50	60	Ω	Required RX D+ as well as D– DC impedance ($50 \pm 20\%$ tolerance). See Notes 2 and 5.
$Z_{RX-HIGH-IMP-DC}$	Powered down DC input impedance	200 k	—	—	Ω	Required RX D+ as well as D– DC impedance when the receiver terminations do not have power. See Note 6.
$V_{RX-IDLE-DET-DIFFp-p}$	Electrical idle detect threshold	65	—	175	mV	$V_{RX-IDLE-DET-DIFFp-p} = 2 \times V_{RX-D+} - V_{RX-D-} $ Measured at the package pins of the receiver.
$T_{RX-IDLE-DET-DIFF-ENTERTIME}$	Unexpected electrical idle enter detect threshold integration time	—	—	10	ms	An unexpected electrical idle ($V_{RX-DIFFp-p} < V_{RX-IDLE-DET-DIFFp-p}$) must be recognized no longer than $T_{RX-IDLE-DET-DIFF-ENTERING}$ to signal an unexpected idle condition.

18 Package Description

This section details package parameters, pin assignments, and dimensions.

18.1 Package Parameters for the MPC8544E FC-PBGA

The package parameters for flip chip plastic ball grid array (FC-PBGA) are provided in [Table 61](#).

Table 61. Package Parameters

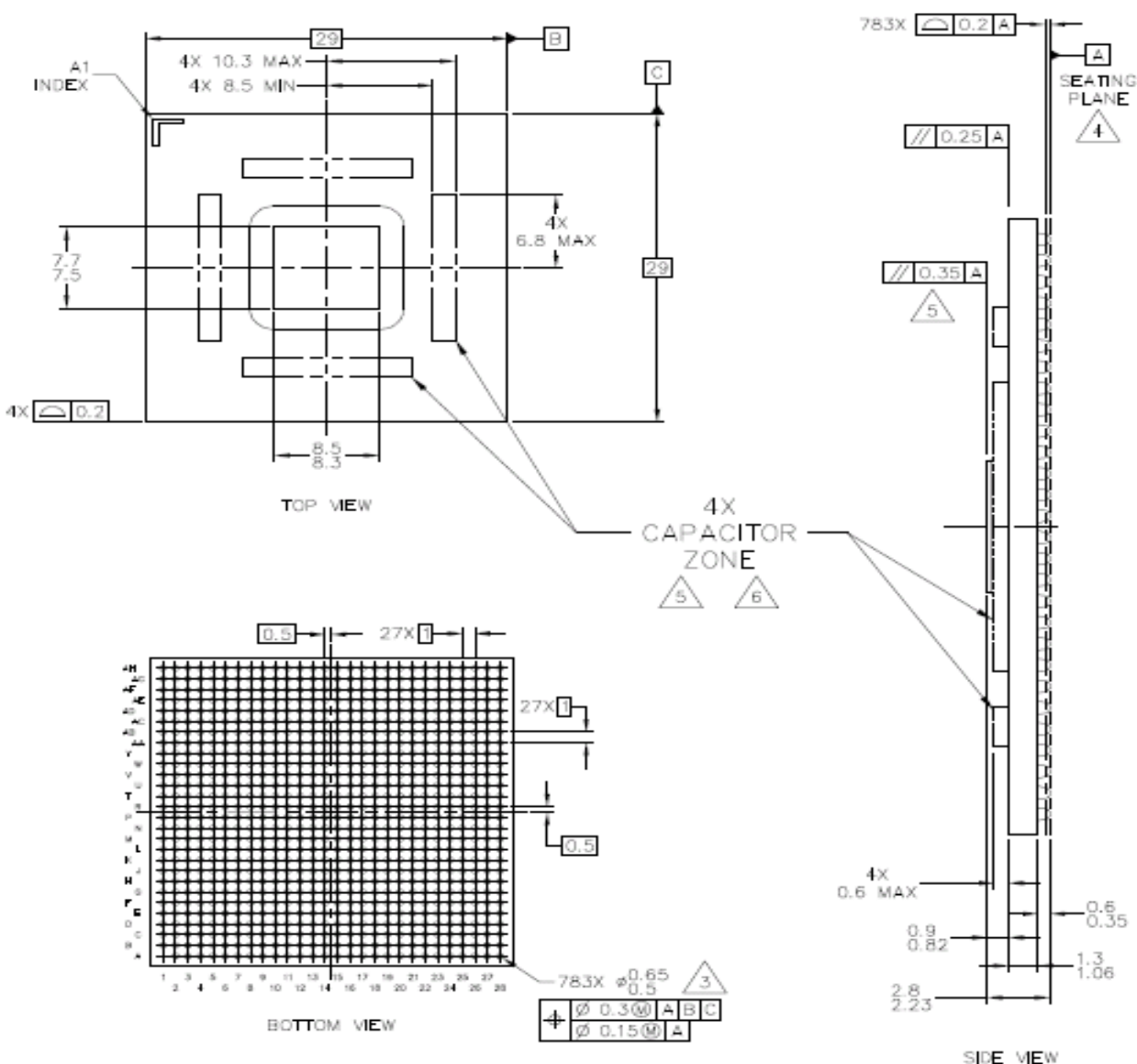
Parameter	PBGA ¹
Package outline	29 mm × 29 mm
Interconnects	783
Ball pitch	1 mm
Ball diameter (typical)	0.6 mm
Solder ball (Pb-free)	96.5% Sn 3.5% Ag

Note:

1. (FC-PBGA) without a lid.

18.2 Mechanical Dimensions of the MPC8544E FC-PBGA

Figure 59 shows the mechanical dimensions and bottom surface nomenclature of the MPC8544E, 783 FC-PBGA package without a lid.



Notes:

1. All dimensions are in millimeters.
2. Dimensions and tolerances per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Parallelism measurement shall exclude any effect of mark on top surface of package.
6. Capacitors may not be present on all parts. Care must be taken not to short exposed metal capacitor pads.
7. All dimensions are symmetric across the package center lines, unless dimensioned otherwise.

Figure 59. Mechanical Dimensions and Bottom Surface Nomenclature of the MPC8544E FC-PBGA without a Lid

Table 62. MPC8544E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Ethernet Management Interface				
EC_MDC	AC7	O	OV _{DD}	4, 8, 14
EC_MDIO	Y9	I/O	OV _{DD}	—
Gigabit Reference Clock				
EC_GTX_CLK125	T2	I	LV _{DD}	—
Three-Speed Ethernet Controller (Gigabit Ethernet 1)				
TSEC1_RXD[7:0]	U10, U9, T10, T9, U8, T8, T7, T6	I	LV _{DD}	—
TSEC1_TXD[7:0]	T5, U5, V5, V3, V2, V1, U2, U1	O	LV _{DD}	4, 8, 14
TSEC1_COL	R5	I	LV _{DD}	—
TSEC1_CRS	T4	I/O	LV _{DD}	16
TSEC1_GTX_CLK	T1	O	LV _{DD}	—
TSEC1_RX_CLK	V7	I	LV _{DD}	—
TSEC1_RX_DV	U7	I	LV _{DD}	—
TSEC1_RX_ER	R9	I	LV _{DD}	4, 8
TSEC1_TX_CLK	V6	I	LV _{DD}	—
TSEC1_TX_EN	U4	O	LV _{DD}	22
TSEC1_TX_ER	T3	O	LV _{DD}	—
Three-Speed Ethernet Controller (Gigabit Ethernet 3)				
TSEC3_RXD[7:0]	P11, N11, M11, L11, R8, N10, N9, P10	I	LV _{DD}	—
TSEC3_TXD[7:0]	M7, N7, P7, M8, L7, R6, P6, M6	O	LV _{DD}	4, 8, 14
TSEC3_COL	M9	I	LV _{DD}	—
TSEC3_CRS	L9	I/O	LV _{DD}	16
TSEC3_GTX_CLK	R7	O	LV _{DD}	—
TSEC3_RX_CLK	P9	I	LV _{DD}	—
TSEC3_RX_DV	P8	I	LV _{DD}	—
TSEC3_RX_ER	R11	I	LV _{DD}	—
TSEC3_TX_CLK	L10	I	LV _{DD}	—
TSEC3_TX_EN	N6	O	LV _{DD}	22
TSEC3_TX_ER	L8	O	LV _{DD}	4, 8
DUART				
UART_CTS[0:1]	AH8, AF6	I	OV _{DD}	—
UART_RTS[0:1]	AG8, AG9	O	OV _{DD}	—

Table 62. MPC8544E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DFT				
L1_TSTCLK	AC20	I	OV _{DD}	18
L2_TSTCLK	AE17	I	OV _{DD}	18
LSSD_MODE	AH19	I	OV _{DD}	18
TEST_SEL	AH13	I	OV _{DD}	3
Thermal Management				
TEMP_ANODE	Y3	—	—	13
TEMP_CATHODE	AA3	—	—	13
Power Management				
ASLEEP	AH17	O	OV _{DD}	8, 15, 21
Power and Ground Signals				
GND	D5, M10, F4, D26, D23, C12, C15, E20, D8, B10, E3, J14, K21, F8, A3, F16, E12, E15, D17, L1, F21, H1, G13, G15, G18, C6, A14, A7, G25, H4, C20, J12, J15, J17, F27, M5, J27, K11, L26, K7, K8, L12, L15, M14, M16, M18, N13, N15, N17, N2, P5, P14, P16, P18, R13, R15, R17, T14, T16, T18, U13, U15, U17, AA8, U6, Y10, AC21, AA17, AC16, V4, AD7, AD18, AE23, AF11, AF14, AG23, AH9, A27, B28, C27	—	—	—
OV _{DD} [1:17]	Y16, AB7, AB10, AB13, AC6, AC18, AD9, AD11, AE13, AD15, AD20, AE5, AE22, AF10, AF20, AF24, AF27	Power for PCI and other standards (3.3 V)	OV _{DD}	—
LV _{DD} [1:2]	R4, U3	Power for TSEC1 interfaces (2.5 V, 3.3 V)	LV _{DD}	—
TV _{DD} [1:2]	N8, R10	Power for TSEC3 interfaces (2.5 V, 3.3 V)	TV _{DD}	—
GV _{DD}	B1, B11, C7, C9, C14, C17, D4, D6, R3, D15, E2, E8, C24, E18, F5, E14, C21, G3, G7, G9, G11, H5, H12, E22, F15, J10, K3, K12, K14, H14, D20, E11, M1, N5	Power for DDR1 and DDR2 DRAM I/O voltage (1.8 V, 2.5 V)	GV _{DD}	—
BV _{DD}	L23, J18, J19, F20, F23, H26, J21, J23	Power for local bus (1.8 V, 2.5 V, 3.3 V)	BV _{DD}	—

Note that there is no default for this PLL ratio; these signals must be pulled to the desired values. Also note that the DDR data rate is the determining factor in selecting the CCB bus frequency, since the CCB frequency must equal the DDR data rate.

Table 65. CCB Clock Ratio

Binary Value of LA[28:31] Signals	CCB:SYSCLK Ratio	Binary Value of LA[28:31] Signals	CCB:SYSCLK Ratio
0000	16:1	1000	8:1
0001	Reserved	1001	9:1
0010	Reserved	1010	10:1
0011	3:1	1011	Reserved
0100	4:1	1100	12:1
0101	5:1	1101	Reserved
0110	6:1	1110	Reserved
0111	Reserved	1111	Reserved

19.3 e500 Core PLL Ratio

[Table 66](#) describes the clock ratio between the e500 core complex bus (CCB) and the e500 core clock. This ratio is determined by the binary value of LBCTL, LALE, and LGPL2 at power up, as shown in [Table 66](#).

Table 66. e500 Core to CCB Clock Ratio

Binary Value of LBCTL, LALE, LGPL2 Signals	e500 core:CCB Clock Ratio	Binary Value of LBCTL, LALE, LGPL2 Signals	e500 core:CCB Clock Ratio
000	4:1	100	2:1
001	Reserved	101	5:2
010	Reserved	110	3:1
011	3:2	111	7:2

19.4 PCI Clocks

For specifications on the PCI_CLK, refer to the *PCI 2.2 Local Bus Specifications*.

The use of PCI_CLK is optional if SYSCLK is in the range of 33–66 MHz. If SYSCLK is outside this range then use of PCI_CLK is required as a separate PCI clock source, asynchronous with respect to SYSCLK.

19.5 Security Controller PLL Ratio

Table 67 shows the SEC frequency ratio.

Table 67. SEC Frequency Ratio

Signal Name	Value (Binary)	CCB CLK:SEC CLK
LWE_B	0	2:1 ¹
	1	3:1 ²

Notes:

1. In 2:1 mode the CCB frequency must be operating $\leq$ 400 MHz.
2. In 3:1 mode any valid CCB can be used. The 3:1 mode is the default ratio for security block.

19.6 Frequency Options

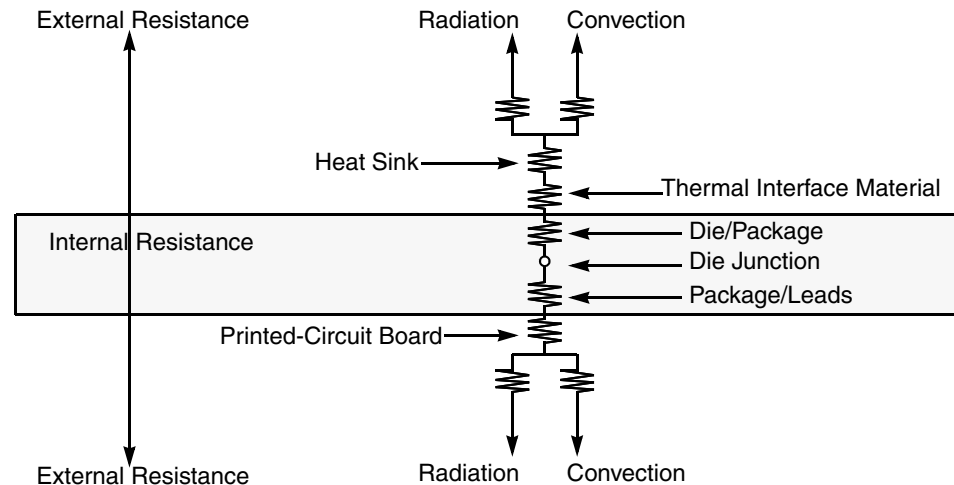
19.6.1 SYSCLK to Platform Frequency Options

Table 68 shows the expected frequency values for the platform frequency when using a CCB clock to SYSCLK ratio in comparison to the memory bus clock speed.

Table 68. Frequency Options of SYSCLK with Respect to Memory Bus Speeds

CCB to SYSCLK Ratio	SYSCLK (MHz)						
	33.33	41.66	66.66	83	100	111	133.33
	Platform /CCB Frequency (MHz)						
2							—
3					—	333	400
4				—	333	400	445
5				333	415	500	
6				400	500		
8			333	533			
9			375				
10	333	417					
12	400	500					
16	533						

Figure 62 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.



(Note the internal versus external package resistance.)

Figure 62. Package with Heat Sink Mounted to a Printed-Circuit Board

The heat sink removes most of the heat from the device. Heat generated on the active side of the chip is conducted through the silicon and through the heat sink attach material (or thermal interface material), and finally to the heat sink. The junction-to-case thermal resistance is low enough that the heat sink attach material and heat sink thermal resistance are the dominant terms.

20.3.2 Thermal Interface Materials

A thermal interface material is required at the package-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by spring clip mechanism, Figure 63 shows the thermal performance of three thin-sheet thermal-interface materials (silicone, graphite/oil, fluoroether oil), a bare joint, and a joint with thermal grease as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. The bare joint results in a thermal resistance approximately six times greater than the thermal grease joint.

Heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 61). Therefore, the synthetic grease offers the best thermal performance, especially at the low interface pressure.

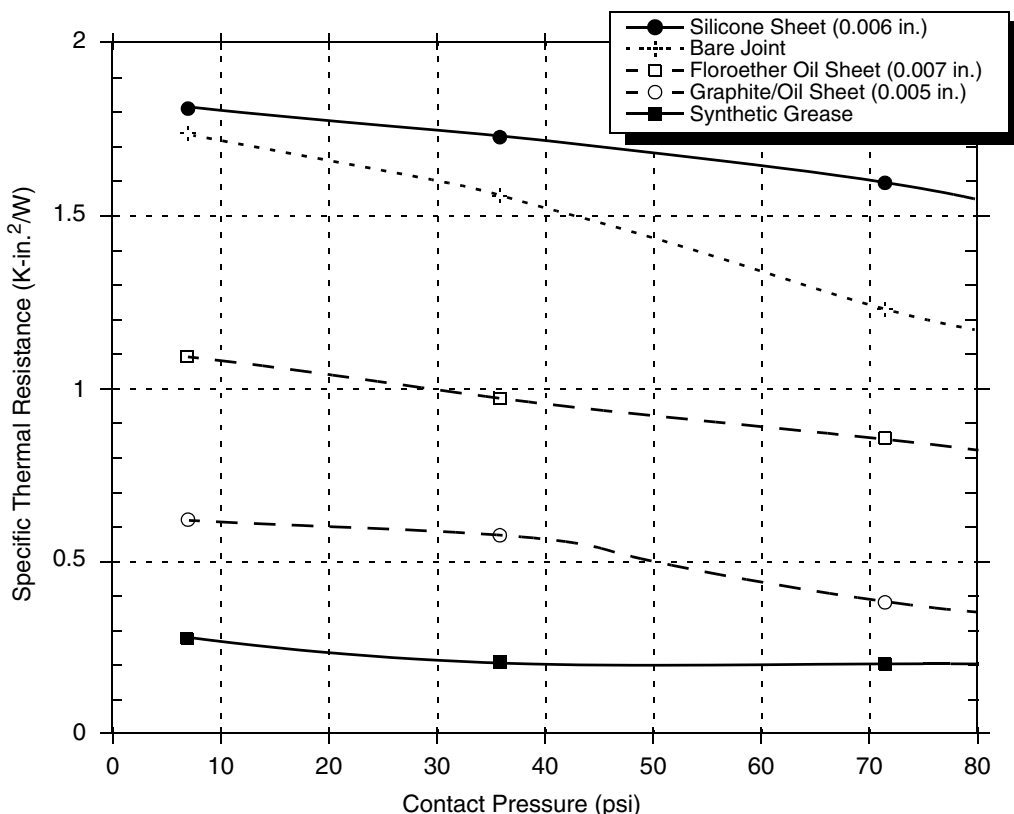


Figure 63. Thermal Performance of Select Thermal Interface Materials

The system board designer can choose between several types of thermal interface. There are several commercially-available thermal interfaces provided by the following vendors:

Chomerics, Inc. 781-935-4850
 77 Dragon Ct.
 Woburn, MA 01801
 Internet: www.chomerics.com

Dow-Corning Corporation 800-248-2481
 Corporate Center
 P.O.Box 999
 Midland, MI 48686-0997
 Internet: www.dow.com

Shin-Etsu MicroSi, Inc. 888-642-7674
 10028 S. 51st St.
 Phoenix, AZ 85044
 Internet: www.microsi.com

The Bergquist Company 800-347-4572
 18930 West 78th St.

21.9.1 Termination of Unused Signals

If the JTAG interface and COP header will not be used, Freescale recommends the following connections:

- $\overline{\text{TRST}}$ should be tied to $\overline{\text{HRESET}}$ through a 0-k Ω isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in Figure 69. If this is not possible, the isolation resistor will allow future access to $\overline{\text{TRST}}$ in case a JTAG interface may need to be wired onto the system in future debug situations.
- No pull-up/pull-down is required for TDI, TMS, or TDO.

Figure 68 shows the COP connector physical pinout.

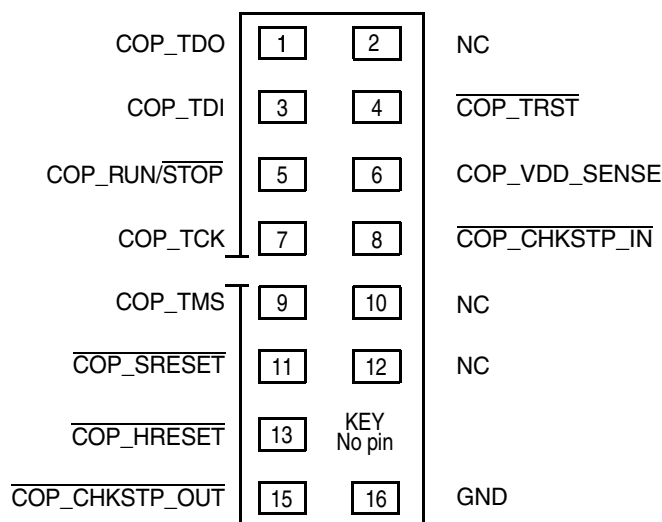
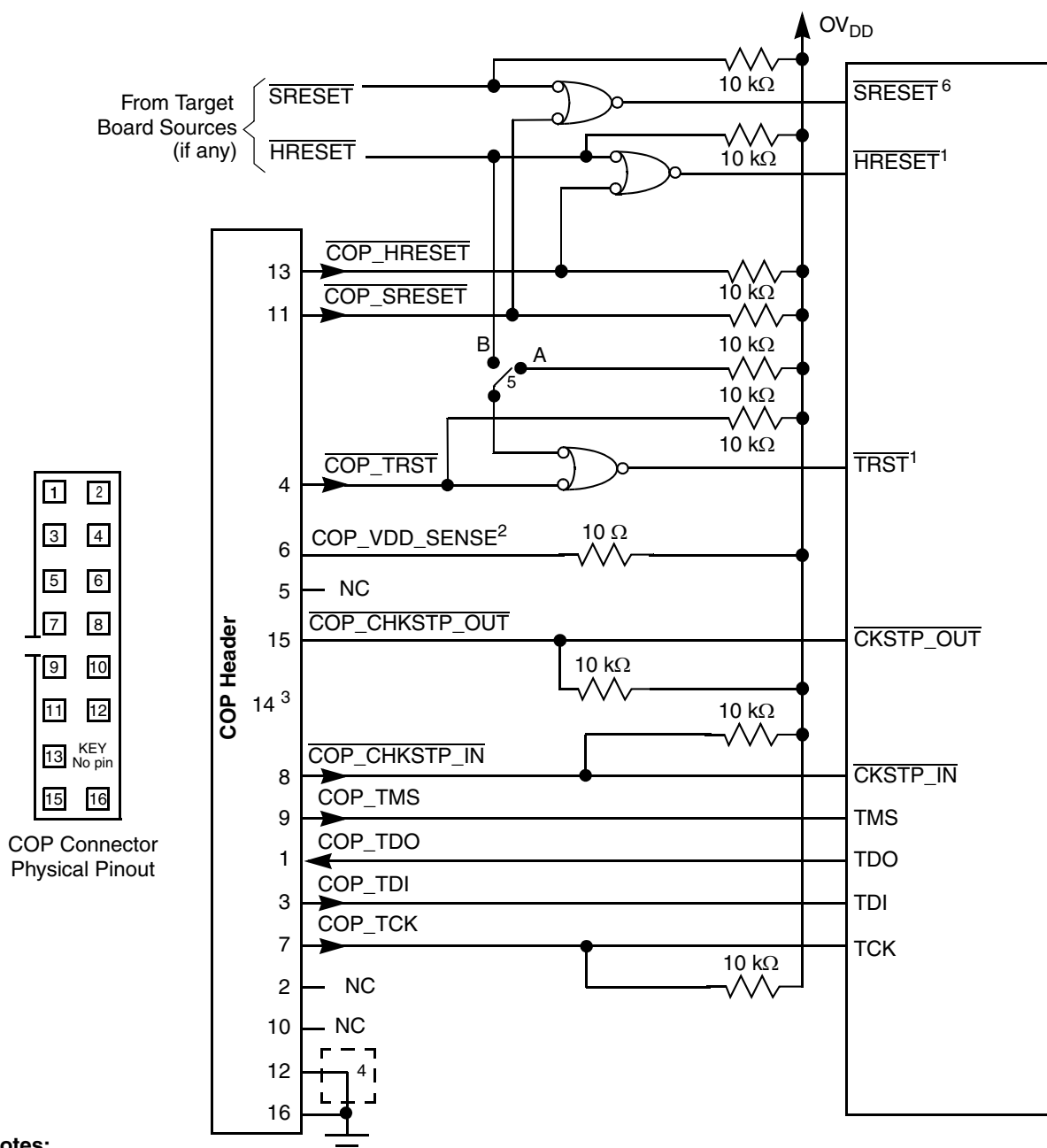


Figure 68. COP Connector Physical Pinout

Figure 69 shows the JTAG interface connection.



Notes:

1. The COP port and target board should be able to independently assert $\overline{\text{HRESET}}$ and $\overline{\text{TRST}}$ to the processor in order to fully control the processor as shown here.
2. Populate this with a 10-Ω resistor for short-circuit/current-limiting protection.
3. The KEY location (pin 14) is not physically present on the COP header.
4. Although pin 12 is defined as a No Connect, some debug tools may use pin 12 as an additional GND pin for improved signal integrity.
5. This switch is included as a precaution for BSDL testing. The switch should be closed to position A during BSDL testing to avoid accidentally asserting the TRST line. If BSDL testing is not being performed, this switch should be closed to position B.
6. Asserting $\overline{\text{SRESET}}$ causes a machine check interrupt to the e500 core.

Figure 69. JTAG Interface Connection

21.10 Guidelines for High-Speed Interface Termination

This section provides guidelines for when the SerDes interface is either not used at all or only partly used.

21.10.1 SerDes Interface Entirely Unused

If the high-speed SerDes interface is not used at all, the unused pin should be terminated as described in this section. However, the SerDes must always have power applied to its supply pins.

The following pins must be left unconnected (float):

- SD_TX[0:7]
- $\overline{\text{SD_TX}}[0:7]$

The following pins must be connected to GND:

- SD_RX[0:7]
- $\overline{\text{SD_RX}}[0:7]$
- SD_REF_CLK
- $\overline{\text{SD_REF_CLK}}$

21.10.2 SerDes Interface Partly Unused

If only part of the high speed SerDes interface pins are used, the remaining high-speed serial I/O pins should be terminated as described in this section.

The following pins must be left unconnected (float) if not used:

- SD_TX[0:7]
- $\overline{\text{SD_TX}}[0:7]$

The following pins must be connected to GND if not used:

- SD_RX[0:7]
- $\overline{\text{SD_RX}}[0:7]$
- SD_REF_CLK
- $\overline{\text{SD_REF_CLK}}$

21.11 Guideline for PCI Interface Termination

PCI termination, if not used at all, is done as follows.

Option 1

- If PCI arbiter is enabled during POR,
- All AD pins will be driven to the stable states after POR. Therefore, all ADs pins can be floating.
- All PCI control pins can be grouped together and tied to OV_{DD} through a single 10-k Ω resistor.
- It is optional to disable PCI block through DEVDISR register after POR reset.